

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:
Hai-Wen CHEN et al.

Application No.: 10/727,039

Confirmation No.: 4864

Filed: December 4, 2003

Art Unit: 2624

For: SYSTEM AND METHOD FOR ESTIMATING
NOISE USING MEASUREMENT BASED
PARAMETRIC FITTING NON-UNIFORMITY
CORRECTION

Examiner: J. W. Lee

AMENDMENT FILED CONCURRENTLY WITH RCE

MS Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

INTRODUCTORY COMMENTS

In response to the Office Action dated November 8, 2007, please amend the above-identified U.S. patent application as follows:

Amendments to the Claims begin on page 2 of this paper.

Remarks/Arguments begin on page 8 of this paper.